

Nano Vibration Analyzer for Vibrational Measurement of Micro Structures



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SIOS Meßtechnik GmbH presents a new fiber-coupled laserinterferometric vibrometer integrated in a precision technical microscope.

The flexible sample positioning in a wide range of 50 mm × 50 mm is achieved by the specific microscope set-up. The vibrating object can be displayed on PC by means of a USB-camera. Different objectives with magnifications of 10× and 50× are available. The laser spot diameter on the object of the 50×-objective is less than 2 µm. The microscope system is adaptable to customer specifications. DC deflection measurements as well as spectral analysis up to a frequency of 2 MHz are possible. The amplitude can be measured with a resolution in sub-nanometer range.

Application areas are vibration measurements of microstructures, MEMS and cantilevers.

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